

<b>Notice of References Cited</b>		Application No.		Applicant(s)	
		09/506,160		CHAI ET AL.	
		Examiner		Group Art Unit	
		Constantine Hanneker		2978	
U.S. PATENT DOCUMENTS					
*	Country Code DOCUMENT NO.	DATE YY-YYYY	NAME		CLASS SUBCLASS
A					
B	US-004549083-A	10-1985	Ozawa		250 452.1
C					
D					
E					
F					
G					
H					
I					
J					
K					
L					
M					
FOREIGN PATENT DOCUMENTS					
*	Country Code DOCUMENT NO.	DATE YY-YYYY	COUNTRY	NAME	CLASS SUBCLASS
N					
O	GB-001338313-A	11-1973	(GB) United Kingdom	(72) Watanabe et al.	-- --
P	DE-002234968-A	1-1973	(DE) West Germany	(72) Watanabe et al.	-- --
Q					
R					
S					
T					
NON-PATENT DOCUMENTS					
*	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)				DATE
U					
V					
W					
X					

\* A copy of this reference is not being furnished with this Office action.  
(See Manual of Patent Examining Procedure, Section 707.05(a).)

<b>Notic of R ferences Cited</b>	Application/Control No. 09/506,160	Applicant(s)/Patent Under Reexamination CHAI ET AL.	
	Examiner Constantine Hannaher	Art Unit 2878	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,859,893-A	01-1999	Moorman et al.	378/154
*	B	US-5,835,561-A	11-1998	Moorman et al.	378/98
*	C	US-5,751,785-A	05-1998	Moorman et al.	378/146
*	D	US-5,729,584-A	03-1998	Moorman et al.	378/146
*	E	US-5,651,047-A	07-1997	Moorman et al.	378/98.8
*	F	US-5,644,612-A	07-1997	Moorman et al.	378/98.2
*	G	US-5,610,967-A	03-1997	Moorman et al.	378/154
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

**Notice of References Cited**

Application/Control No.

10/623,226

Applicant(s)/Patent Under  
Reexamination  
CHAI ET AL.

Examiner

Shun Lee

Art Unit

2878

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,164,041 A	11-1992	Berkstresser et al.	117/19
	B	US-5,500,147 A	03-1996	Fitzpatrick, Brian J.	252/301.6S
	C	US-5,690,731 A	11-1997	Kurata et al.	117/13
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Melcher et al. Czochralski growth of rare earth oxyorthosilicate single crystals. J. of Crystal Growth, Vol. 128 (1993), pp. 1001-1005.
	V	Loutts et al. Czochralski growth and caharcterization of (Lu1-xGdx)2SiO5 single crystals for scintillators. J. of Crystal Growth, Vol. 174 (1997), pp.331-336.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.